

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re new PATENT application of)
Hidekazu MIYAIRI et al.)
Based on Japanese Patent No. 2003-085096) New Applications
Filed: March 26, 2003)
For: METHOD FOR TESTING)
 SEMICONDUCTOR FILM,)
 SEMICONDUCTOR DEVICE AND)
 MANUFACTURING METHOD THEREOF)

PRELIMINARY AMENDMENT

Commissioner of Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Amendments to the Specification begins on page 2 of this paper.

Remarks begin on page 3 of this paper.